

Attorney Docket No. 0553-0401

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of:

Yoshifumi TANADA

Serial No.: 10/807,692

Filed: March 24, 2004

Art Unit: 2819

Examiner: Vibol Tan

For: CIRCUIT FOR INSPECTING SEMICONDUCTOR  
DEVICE AND INSPECTING METHOD

) I hereby certify that this correspondence is  
) being deposited with the United States  
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) Shannon Wallace

) Date: February 15 2006

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 C.F.R. §1.97, Applicant hereby calls the Examiner's attention to documents listed on the attached form, which documents may be material to the examination of this application. Pursuant to 37 CFR §1.98(a)(2)(i) copies of cited US patent and US patent application publications are not submitted herewith. Copies of foreign patent documents and non-patent literature documents are enclosed herewith for the Examiner's consideration.

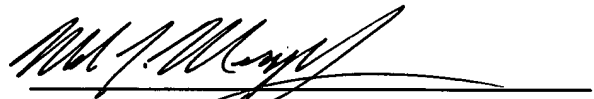
No inference should be drawn that the attached list sets forth a comprehensive investigation of the prior art, that any or all are pertinent to the invention, or that any apparatus disclosed is equivalent to the subject invention.

The citation of the above-discussed documents is not to be construed as an assertion that more pertinent art could not possibly be in existence. Citation of any document herein is not to be construed as an admission that any subject matter disclosed in the document is necessarily within the inventive field of endeavor, that any disclosure is necessarily prior in time to a particular date which may be relevant to the instant patent application, and/or that any disclosure is otherwise necessarily prior art with respect to the instant invention.

Applicant also respectfully reserves the right to later set forth how the instant invention is distinguished over the disclosure of any document or other art, including the disclosure of those documents discussed herein, that may be cited by the Examiner in rejecting a claim in the instant patent application.

As an RCE is being filed herewith, no fee is believed necessary for this IDS. If a fee is required, please charge Deposit Account No. 50/1039.

Respectfully submitted,

  
Mark J. Murphy  
Registration No: 34,225

COOK, ALEX, McFARRON, MANZO,  
CUMMINGS & MEHLER, LTD.  
200 West Adams Street  
Suite 2850  
Chicago, Illinois 60606  
(312) 236-8500

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LIST OF PUBLICATIONS CITED BY APPLICANT			Atty Docket No. 0553-0401		Serial No. 10/807,692	
			Applicant Yoshifumi TANADA			
			Filing Date March 24, 2004		Group 2819	
<b>U.S. PATENT DOCUMENTS</b>						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	US 2001/ 0035526 A1	11/01/01	Yamazaki et al	257	57	04/24/01
	US 2001/ 0040565 A1	11/15/01	Koyama	345	204	05/11/01
	US 2002/ 0130675 A1	09/19/02	Hiroki	324	750	03/18/02
	US 2002/ 0132383 A1	09/19/02	Hiroki et al	438	17	03/18/02
	US 2004/ 0119824 A1	06/24/04	Osada	348	180	12/11/03
	6,762,735 B2	07/13/04	Koyama	345	76	05/11/01
	US 2004/ 0239598 A1	12/02/04	Koyama	345	76	06/15/04
	6,850,080 B2	02/01/05	Hiroki	324	750	03/18/02
	US 2005/ 0212044 A1	09/29/05	Hiroki	257	347	01/21/05
<b>FOREIGN PATENT DOCUMENTS</b>						
	DOCUMENT NUMBER	DATE	APPLICANT	English Abstract	English Trans.	FILING DATE
	JP 2002- 014337	01/18/02	Semiconductor Energy Lab Co. Ltd	X		04/26/01
	JP 2002- 032035	01/31/02	Semiconductor Energy Lab Co. Ltd	X		05/10/01
	JP 2002- 350513	12/04/02	Semiconductor Energy Lab Co. Ltd	X		03/12/02
	JP 2003- 031814	01/31/03	Semiconductor Energy Lab Co. Ltd	X		03/19/02

**OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS**

(Include name of author (in CAPITAL LETTERS), title of article or item (book, magazine, journal, serial, symposium, catalog, etc.) date, pages(s), volume-issue number(s), publisher, city and/or country where published).

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EXAMINER:

DATE CONSIDERED:

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP form. Draw line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.